

N-Channel 650V (D-S) Power MOSFET

PRODUCT SUMMA	RY	
V _{DS} (V) at T _J max.	650)
R _{DS(on)} max. at 25 °C (Ω)	V _{GS} = 10 V	0.68
Q _g max. (nC)	43	
Q _{gs} (nC)	5	
Q _{gd} (nC)	22	
Configuration	Sing	le

FEATURES

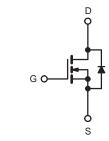
• Low figure-of-merit (FOM) Ron x Qa



- Reduced switching and conduction losses
- Ultra low gate charge (Q_a)
- Avalanche energy rated (UIS)

APPLICATIONS

- Server and telecom power supplies
- Switch mode power supplies (SMPS)
- Power factor correction power supplies (PFC)
- Lighting
 - High-intensity discharge (HID)
 - Fluorescent ballast lighting
- Industrial



N-Channel MOSFET

G D S
Top View

TO-220 FULLPAK

ABSOLUTE MAXIMUM RATINGS (T _C = 25 °C, unless otherwise noted)							
PARAMETER			SYMBOL	LIMIT	UNIT		
Drain-Source Voltage			V_{DS}	650	V		
Gate-Source Voltage			V_{GS}	± 30	7 v		
Continuous Drain Current (T _J = 150 °C)	\/ at 10 \/	T _C = 25 °C		12			
	V _{GS} at 10 V	T _C = 100 °C	ΙD	9.4	Α		
Pulsed Drain Current ^a			I _{DM}	45			
Linear Derating Factor				3.6	W/°C		
Single Pulse Avalanche Energy b			E _{AS}	290	mJ		
Maximum Power Dissipation			P_{D}	106 /34	W		
Operating Junction and Storage Temperature Range			T _J , T _{stg}	-55 to +150	°C		
Drain-Source Voltage Slope	T _J = 125 °C		-1\//-1+	15	\//		
Reverse Diode dV/dt d			dV/dt	4.1	V/ns		
Soldering Recommendations (Peak Temperature) ^c	perature) c for 10 s			300	°C		

- a. Repetitive rating; pulse width limited by maximum junction temperature. b. $V_{DD}=50$ V, starting T_J = 25 °C, L = 28.2 mH, R_g = 25 Ω , I_{AS} = 4.5 A.
- c. 1.6 mm from case.
- d. $I_{SD} \le I_D$, dI/dt = 100 A/ μ s, starting $T_J = 25$ °C.



THERMAL RESISTANCE RATI	NGS			
PARAMETER	SYMBOL	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	R _{thJA}	-	60	°C/W
Maximum Junction-to-Case (Drain)	R_{thJC}	-	0.8	G/ VV

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static		-					
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} :	= 0 V, I _D = 250 μA	650	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	e to 25 °C, I _D = 1 mA	-	0.75	-	V/°C
Gate-Source Threshold Voltage (N)	V _{GS(th)}	V _{DS} =	= V _{GS} , I _D = 250 μA	3	-	5	V
			V _{GS} = ± 20 V	-	-	± 100	nA
Gate-Source Leakage	I_{GSS}		V _{GS} = ± 30 V	-	_	± 1	μA
			= 650 V, V _{GS} = 0 V	-	-	1	
Zero Gate Voltage Drain Current	I_{DSS}		/, V _{GS} = 0 V, T _J = 125 °C	-	_	10	μA
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 8 A	-	0.65	-	Ω
Forward Transconductance	9fs	V _{DS}	s = 30 V, I _D = 8 A	-	16	-	S
Dynamic		•					
Input Capacitance	C _{iss}	$V_{GS} = 0 \text{ V},$ $V_{DS} = 100 \text{ V},$		-	1600	-	pF
Output Capacitance	Coss			-	300	-	
Reverse Transfer Capacitance	C _{rss}	7	f = 1 MHz		200	-	
Effective Output Capacitance, Energy Related ^a	C _{o(er)}	V _{DS} = 0 V to 520 V, V _{GS} = 0 V		-	63	-	
Effective Output Capacitance, Time Related ^b	C _{o(tr)}			-	213	-	
Total Gate Charge	Q_g			-	43	96	
Gate-Source Charge	Q _{gs}	V _{GS} = 10 V	$I_D = 8 A, V_{DS} = 520 V$	-	5	-	nC
Gate-Drain Charge	Q _{gd}	1		-	22	-	1
Turn-On Delay Time	t _{d(on)}	$V_{DD} = 520 \text{ V}, I_D = 8 \text{ A}, V_{GS} = 10 \text{ V}, R_g = 9.1 \Omega$		-	13	25	ns
Rise Time	t _r			-	11	35	
Turn-Off Delay Time	t _{d(off)}			-	81	90	
Fall Time	t _f		1		25	40	
Gate Input Resistance	R_g	f = 1 MHz, open drain		-	3.5	-	Ω
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	I _S	MOSFET sym	MOSFET symbol showing the		-	15	
Pulsed Diode Forward Current	I _{SM}	integral reverse p - n junction diode		-	-	40	A
Diode Forward Voltage	V _{SD}	T _J = 25 °C, I _S = 8 A, V _{GS} = 0 V		-	-	1.5	V
Reverse Recovery Time	t _{rr}	-		-	345	-	ns
Reverse Recovery Charge	Q _{rr}	$T_J = 25 \text{ °C}, I_F = I_S = 8 \text{ A},$ $dI/dt = 100 \text{ A/}\mu\text{s}, V_R = 400 \text{ V}$		-	4.5	-	μC
Reverse Recovery Current	I _{RRM}				35		A

Notes

- a. $C_{oss(er)}$ is a fixed capacitance that gives the same energy as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DSS} . b. $C_{oss(tr)}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DSS} .



TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

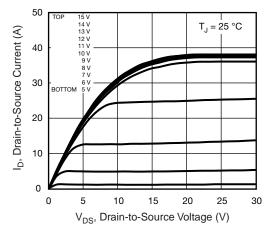


Fig. 1 - Typical Output Characteristics

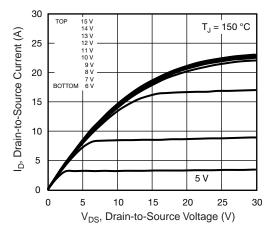


Fig. 2 - Typical Output Characteristics

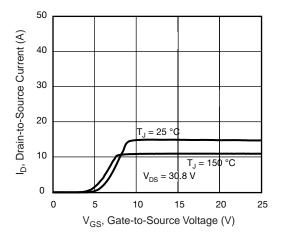


Fig. 3 - Typical Transfer Characteristics

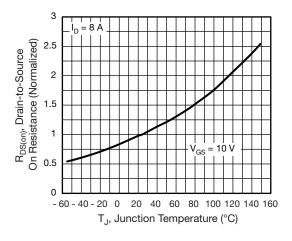


Fig. 4 - Normalized On-Resistance vs. Temperature

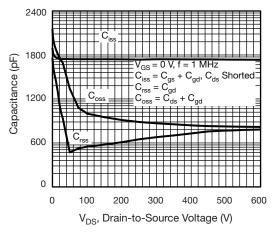


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

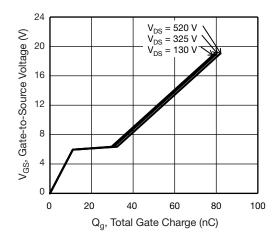


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage



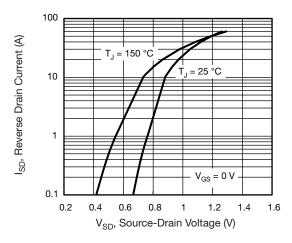


Fig. 7 - Typical Source-Drain Diode Forward Voltage

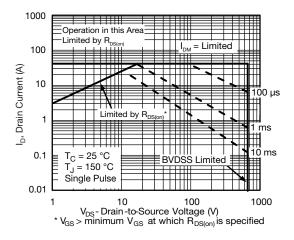


Fig. 8 - Maximum Safe Operating Area

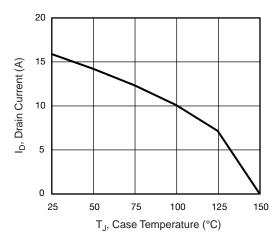


Fig. 9 - Maximum Drain Current vs. Case Temperature

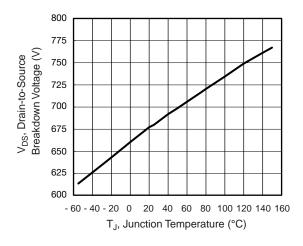


Fig. 10 - Temperature vs. Drain-to-Source Voltage

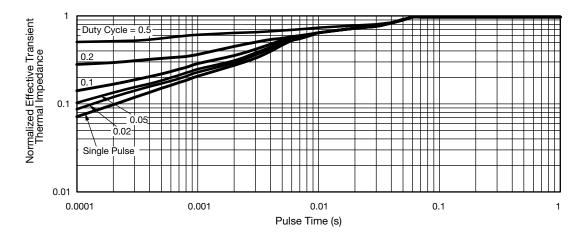


Fig. 11 - Normalized Thermal Transient Impedance, Junction-to-Case



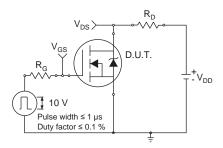


Fig. 12 - Switching Time Test Circuit

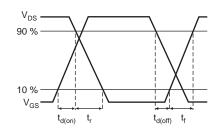


Fig. 13 - Switching Time Waveforms

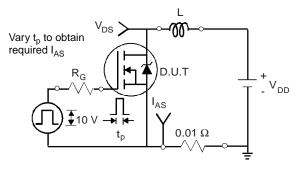


Fig. 14 - Unclamped Inductive Test Circuit

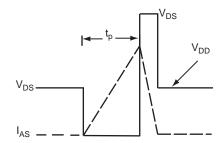


Fig. 15 - Unclamped Inductive Waveforms

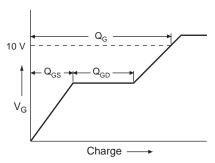


Fig. 16 - Basic Gate Charge Waveform

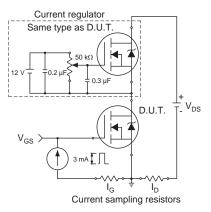
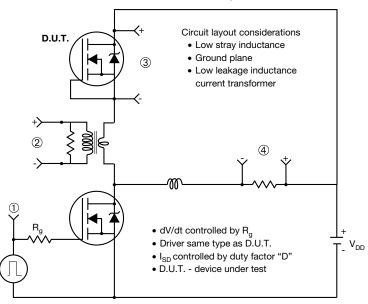


Fig. 17 - Gate Charge Test Circuit

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Peak Diode Recovery dV/dt Test Circuit



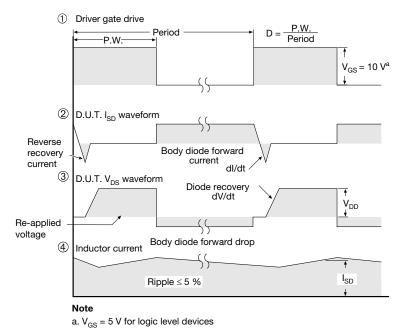
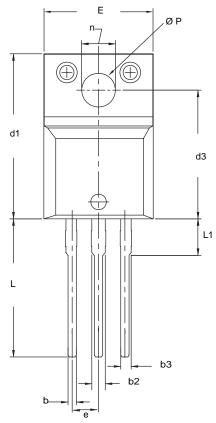
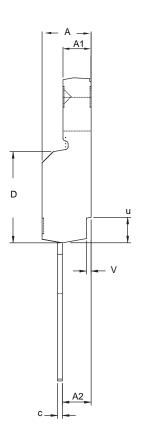


Fig. 18 - For N-Channel



TO-220 FULLPAK (HIGH VOLTAGE)





DIM.	MILLIM	IETERS	INCHES	
	MIN.	MAX.	MIN.	MAX.
Α	4.570	4.830	0.180	0.190
A1	2.570	2.830	0.101	0.111
A2	2.510	2.850	0.099	0.112
b	0.622	0.890	0.024	0.035
b2	1.229	1.400	0.048	0.055
b3	1.229	1.400	0.048	0.055
С	0.440	0.629	0.017	0.025
D	8.650	9.800	0.341	0.386
d1	15.88	16.120	0.622	0.635
d3	12.300	12.920	0.484	0.509
E	10.360	10.630	0.408	0.419
е	2.54	BSC	0.100 BSC	
L	13.200	13.730	0.520	0.541
L1	3.100	3.500	0.122	0.138
n	6.050	6.150	0.238	0.242
ØΡ	3.050	3.450	0.120	0.136
u	2.400	2.500	0.094	0.098
V	0.400	0.500	0.016	0.020

ECN: X09-0126-Rev. B, 26-Oct-09 DWG: 5972

- To be used only for process drawing.
 These dimensions apply to all TO-220, FULLPAK leadframe versions 3 leads.
 All critical dimensions should C meet C_{pk} > 1.33.
 All dimensions include burrs and plating thickness.
 No chipping or package damage.



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